

# MQ40 High-Q MLCC

## 1 Features

- 1) Ultra-low ESR, ESL, high self-resonance frequency;
- 2) New material systems, excellent performance, ultra-high Q, good frequency-selection characteristics;
- 3) No Capacitance shift with Temperature variance;
- 4) Applicable to mobile base station and terminal devices;
- 5) Small case sizes are available.



## 2 Applications

Function: Bypass, Coupling, Tuning, Feedback, Impedance Matching and DC Blocking.

Circuits: MW/RF/Mid-frequency Amplifier, Frequency mixer, Oscillator, low-noise amplifier, Filter Network, Timing and Time Delay. Terminal Applications: Mobile Base Stations, Mobile Phone, WiFi, IoT, Etc.

## 3 How to Order

MQ	40	0603	C0G	2E	101	J	N	7	R
Type	Series	Case Size Code	TCC	Rated V.	Nominal Capacitance	Capacitance Tolerance	Termination Type	Thickness Code	Packaging
Table 1	Table 2	Table 3	Table 4	Table 5	Table 6	Table 7	Table 8	Table 3	Table 9

Table 1 Product Type

MQ	High-Q MLCC
----	-------------

Table 2 Product Series

40	Ultra-low ESR, applicable to consumer electronics. Case sizes of 0402, 0603, 0805 available
----	---

Table 3 Case Size Code(mm)

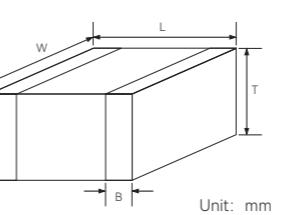
Drawing 	Case Size Code	0402	0603	0805
	Thickness code	B	7	C
	L	1.00 ± 0.05	1.60 ± 0.15	2.00 ± 0.15
	W	0.50 ± 0.05	0.80 ± 0.15	1.25 ± 0.15
	T	0.50 ± 0.05	0.70 ± 0.10	0.85 ± 0.15
	B	0.25 ± 0.10	0.35 ± 0.15	0.45 ± 0.25

Table 4 Temperature Coefficient

Code	TCC	Working Temperature
C0G	0±30ppm/°C	-55°C ~ 125°C

Table 5 Rated Voltage

2D	200V	2E	250V
----	------	----	------

Table 6 Nominal Capacitance

EIA Capacitance code in pF. 1st two digit are significant figures of capacitance; 3rd digit denotes number of Zeros;  
R=decimal point; For examples: 103=10,000pF; 3R9=3.9pF.



# MQ40 High-Q MLCC

## 5 Electrical Specifications&Test Conditions

Item	Test Conditions (25°C ±2°C)	Electrical Specifications
Capacitance	Test Frequency: 1MHz±10%	Capacitance values are up to requirements
Q	Test Voltage: 1.0Vrms±0.2Vrms	$C_R \geq 30\text{pF}, Q \geq 1400;$ $C_R < 30\text{pF}, Q \geq 800+20C \quad (C=C_R/\text{pF})$
Insulation Resistance R <sub>i</sub>	Test Voltage:rated Voltage U <sub>R</sub> Endurance time: 2min±5s	$R_i \geq 104\text{M}\Omega$
Withstanding Voltage	2.5U <sub>R</sub> ,5s±1s, Surge current≤ 50mA	No breakdown, flashover or visible damages

## 6 Reliability Characteristics&Test Conditions

Item	Test Conditions	Reliability Characteristics
Thermal Shock	Upper limit:125°C; Lower limit:-55°C; Recycle times:5; Endurance:30min.	No visible damages to appearance. Capacitance change less than ±2.5% or ±0.25pF(Whichever is wider)
Resistance to soldering heat	Slot Weld Preheat at 110°C~140°C,endure 30s~60s. Temperature:260°C±5°C; Dip time:10s ±1s; Dip depth:10mm; Dip time:1 time; recover:6h~24h.	No visible damages, cracks or exposure of inner electrodes. The peeling of Termination coating is less than 25%; Capacitance values variation is within ±2.5% or ±0.25pF, Whichever is wider.
Resistance to Humidity in Steady State	Temperature:40°C ±2°C; Relative humidity:90~95%; Endure:21d (500+10) h; Withstanding Voltage Test within 15min after test finish:UR,5s; Recover:6h~24h.	Capacitance:Compared with initial value, $\Delta C/C \leq 7.5\%$ or 0.75pF,whichever is higher; $Q \geq 200 \quad (C_R \geq 30\text{pF})$ $Q \geq 100+10C/3 \quad (C_R < 30\text{pF})$ $(C=C_R/\text{pF})$ Insulation resistance: $R_i \geq 500\text{M}\Omega$
High-temperature Life Test	Time endure:1000h; Test temperature:125°C; Test voltage: 2U <sub>R</sub> .	Capacitance:Compared with initial value, $\Delta C/C \leq 3\%$ or 0.30pF,whichever is higher; $Q \geq 350 \quad (C_R \geq 30\text{pF})$ $Q \geq 275+5C/2 \quad (10\text{pF} \leq C_R < 30\text{pF})$ $Q \geq 200+10C \quad (C_R < 10\text{pF})$ $(C=C_R/\text{pF})$ Insulation resistance: $R_i \geq 1000\text{M}\Omega$

# MQ40 High-Q MLCC

## 7 Performance Data

Temperature Coefficient

Capacitance VS Temperature

